



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Philip LeBlanc
 Serial No. : 10/626,309
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 For : FIBER ARRAY INTERFEROMETER FOR
 INSPECTING GLASS SHEETS

MODIFIED 1449 FORMU.S. PATENT DOCUMENTS

<u>Examiner Initial</u>		<u>Document Number</u>	<u>Issue Date</u>	<u>Name</u>
<u>MAL</u>	1.	4,340,304	7/1982	Massie
↑	2.	4,844,616	7/1989	Kulkarni et al.
	3.	5,017,010	5/1991	Mamin et al.
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13. Rugar et al., "Improved fiber-optic interferometer for atomic force microscopy," Appl. Phys. Lett., 55,2588-2590 (1989).

M. d. P. A. /

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ATTORNEY DOCKET NO.

SERIAL NO.

LIST OF PATENTS AND
PUBLICATIONS

SP03-089

10/626,309

FOR APPLICANTS INFORMATION
DISCLOSURE STATEMENT

APPLICANT: Philip Robert LeBlanc, et al.

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GROUP: 2877

REFERENCE DESIGNATION

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Examiner- Initial		Document Number	Date	Name	Class	Sub- Class	Filing Date if Approp.
MM	AA	3,633,031	1/4/1972	Pesce et al	1	1	
	AB	4,928,527	5/29/1990	Burger et al	1	1	
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MM	AE	5,402,236	3/28/1995	Brown et al	1	1	
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OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

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EXAMINER:

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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609: draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.